

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/758,983	YAMAKAWA ET AL.	
	Examiner	Art Unit	
	Patricia T. Nguyen	2817	

SEARCHED

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
333	202	10/15/2005	PN
	206		
	207		
333/219.1			